

January 1989

## High Frequency/Video Switch

### Features

- This Circuit Is Processed in Accordance to Mil-Std-883 and Is Fully Conformant Under the Provisions of Paragraph 1.2.1.
- Wideband Operation ..... 150 MHz
- Differential Gain ..... 0.03% (Typ)  
0.1% (Max)
- Differential Phase ..... 0.003 Degrees (Typ)  
0.01 Degrees (Max)
- Switching Speed ..... 100ns (Typ)  
200ns (Max)
- $R_{ON}$  ..... 35Ω (Typ)  
75Ω (Max)
- Off Isolation @ 10 MHz ..... -65dB (Typ)  
-60dB (Max)
- Crosstalk @ 10 MHz ..... -80dB (Typ)  
-75dB (Max)

### Description

The HI-222/883 is a high frequency analog switch that complements the Harris family of high speed op amps and buffers. Fabricated with our Dielectric Isolation process and using silicon gate technology, many key parameters have been enhanced.

Crosstalk and off isolation are optimized with a T-switch configuration and the use of nonconnected pins for extended shielding. Other features of the HI-222/883 include wideband operation, low  $R_{ON}$ , fast switching speeds and low differential gain and phase. The characteristics of this TTL compatible device make it ideal for designs where improved switching performance is required.

The primary application of this dual SPST switch is the routing of high frequency signals in equipment ranging from video production mixers to military RF circuits.

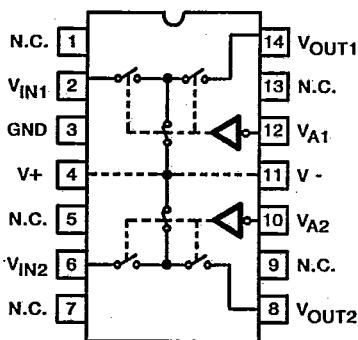
The HI-222/883 is available in a 14 pin Ceramic DIP or a 20 pin Ceramic LCC and is specified over the -55°C to +125°C temperature range.

### Applications

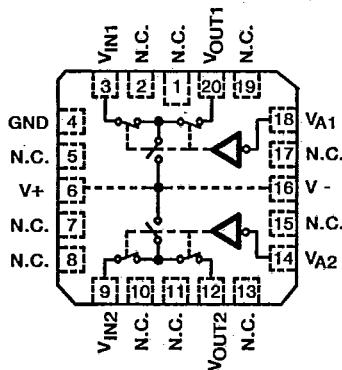
- Routing Switchers
- Medical Imaging
- Production Mixers
- Heads-Up Displays
- High Definition TV
- Simulators
- Radar Signal Conditioning
- Sonar

### Pinouts

HI1-222/883 (CERAMIC DIP)  
 LOGIC "1" INPUT  
 TOP VIEW



HI4-222/883 (CERAMIC LCC)  
 LOGIC "0" INPUT  
 TOP VIEW



NOTE: Source and Drain are arbitrarily depicted as Analog Input and Output, respectively. They may be interchanged without affecting performance.  
 All nonconnected pins should be tied to ground.

**Absolute Maximum Ratings**

Voltage Between V+ and V- Terminals.....	36V
$\pm V_{SUPPLY}$ to Ground (V+, V-) .....	$\pm 18V$
Digital and Analog Input Voltage (V <sub>A</sub> , V <sub>S</sub> , V <sub>D</sub> ).....	+V <sub>SUPPLY</sub> +2V -V <sub>SUPPLY</sub> -2V

**Peak Current (Source to Drain)**

(Pulse at 0.8ms, 10% Duty Cycle Max)..... 100mA

Peak Current (Any Pin, 50% Duty Cycle)..... 28mA

Continuous Current (Any Pin)..... 15mA

Junction Temperature ..... +175°C

Storage Temperature Range ..... -65°C to +150°C

ESD Rating ..... &lt; 2000V

Lead Temperature (Soldering 10 sec)..... 300°C

**Thermal Information**

	$\theta_{ja}$	$\theta_{jc}$
Ceramic DIP Package .....	75°C/W	17°C/W
Ceramic LCC Package .....	76°C/W	19°C/W
Package Power Dissipation Limit at +75°C .....		
Ceramic DIP Package .....	1.0W	
Ceramic LCC Package .....	1.0W	
Package Power Dissipation Derating Factor Above +75°C .....		
Ceramic DIP Package .....	13.4mW/°C	
Ceramic LCC Package .....	13.2mW/°C	

CAUTION: Absolute maximum ratings are limiting values, applied individually, beyond which the serviceability of the circuit may be impaired. Functional operability under any of these conditions is not necessarily implied.

**Recommended Operating Conditions**

Operating Temperature Range ..... -55°C to +125°C

Operating Supply Voltage .....  $\pm 15V$ Analog Input Voltage (V<sub>S</sub>).....  $\pm V_{SUPPLY}$ 

Address Low Level (VAL) ..... 0V to 0.8V

Address High Level (V<sub>AH</sub>) ..... 2.0V to +5.0V

Ground All Nonconnected Pins.

TABLE 1. D.C. ELECTRICAL PERFORMANCE CHARACTERISTICS

Device Tested at: Supply Voltage =  $\pm 15V$ , V<sub>AH</sub> = 2.0V, VAL = +0.8V, Unused Pins are Grounded.

D.C. PARAMETERS	SYMBOL	CONDITIONS	GROUP A SUBGROUP	TEMPERATURE	LIMITS		UNITS
					MIN	MAX	
Switch "ON" Resistance	R <sub>DS</sub>	V <sub>D</sub> = 5V, I <sub>S</sub> = 7.5mA S1/S2	1	+25°C	-	60	$\Omega$
			2, 3	-55°C to +125°C	-	75	$\Omega$
		V <sub>D</sub> = -5V, I <sub>S</sub> = -7.5mA S1/S2	1	+25°C	-	60	$\Omega$
			2, 3	-55°C to +125°C	-	75	$\Omega$
Source "OFF" Leakage Current	I <sub>S(OFF)</sub>	V <sub>S</sub> = 5V, V <sub>D</sub> = -5V S1/S2	1	+25°C	-2.5	2.5	nA
			2, 3	-55°C to +125°C	-200	200	nA
		V <sub>S</sub> = -5V, V <sub>D</sub> = 5V S1/S2	1	+25°C	-2.5	2.5	nA
			2, 3	-55°C to +125°C	-200	200	nA
Drain "OFF" Leakage Current	I <sub>D(OFF)</sub>	V <sub>D</sub> = 5V, V <sub>S</sub> = -5V S1/S2	1	+25°C	-2.5	2.5	nA
			2, 3	-55°C to +125°C	-200	200	nA
		V <sub>D</sub> = -5V, V <sub>S</sub> = 5V S1/S2	1	+25°C	-2.5	2.5	nA
			2, 3	-55°C to +125°C	-200	200	nA
Channel "ON" Leakage Current	I <sub>D(ON)</sub>	V <sub>D</sub> = V <sub>S</sub> = 5V S1/S2	1	+25°C	-2.5	2.5	nA
			2, 3	-55°C to +125°C	-200	200	nA
		V <sub>D</sub> = V <sub>S</sub> = -5V S1/S2	1	+25°C	-2.5	2.5	nA
			2, 3	-55°C to +125°C	-200	200	nA
Low Level Address Current	I <sub>AL</sub>	V <sub>A</sub> = 0.8V A <sub>1</sub> , A <sub>2</sub>	1	+25°C	-	1.0	$\mu$ A
			2, 3	-55°C to +125°C	-	1.0	$\mu$ A
High Level Address Current	I <sub>AH</sub>	V <sub>A</sub> = 2.0V A <sub>1</sub> , A <sub>2</sub>	1	+25°C	-	1.0	$\mu$ A
			2, 3	-55°C to +125°C	-	1.0	$\mu$ A
Positive Supply Current	+I <sub>CC</sub>	V <sub>A</sub> = 0.8V, 2.0V A <sub>1</sub> , A <sub>2</sub>	1	+25°C	-	4.0	mA
			2, 3	-55°C to +125°C	-	6.0	mA
Negative Supply Current	-I <sub>CC</sub>	V <sub>A</sub> = 0.8V, 2.0V A <sub>1</sub> , A <sub>2</sub>	1	+25°C	-4.0	-	mA
			2, 3	-55°C to +125°C	-6.0	-	mA

4  
CMOS ANALOG SWITCHES

CAUTION: This device is sensitive to electrostatic discharge. Proper I.C. handling procedures should be followed.

T-51-11

TABLE 2. A.C. ELECTRICAL PERFORMANCE CHARACTERISTICS

Device Tested at: Supply Voltage =  $\pm 15V$ ,  $V_{AH} = 2.0V$ ,  $V_{AL} = 0.8V$ , Ground All Nonconnected Pins.

PARAMETERS	SYMBOL	CONDITIONS	GROUP A SUBGROUPS	TEMPERATURE	LIMITS		UNITS
					MIN	MAX	
Turn "ON" Time	$t_{ON}$	$V_S = 5V$ $C_L = 35pF$ $R_L = 2k\Omega$	9	+25°C	-	150	ns
			10, 11	-55°C, +125°C	-	200	ns
Turn "OFF" Time	$t_{OFF}$	$V_S = 5V$ $C_L = 35pF$ $R_L = 2k\Omega$	9	+25°C	-	150	ns
			10, 11	-55°C, +125°C	-	200	ns

TABLE 3. ELECTRICAL PERFORMANCE CHARACTERISTICS (NOTE 1)

Device Characterized at: Supply Voltage =  $\pm 15V$ ,  $V_{AH} = 2.0V$ ,  $V_{AL} = 0.8V$ , Ground All Nonconnected Pins.

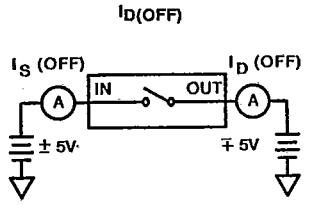
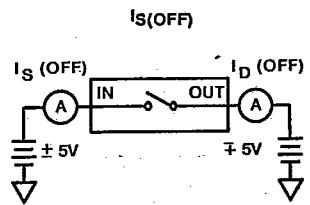
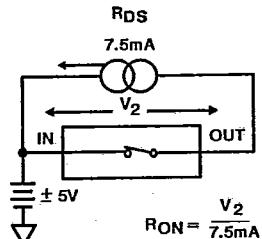
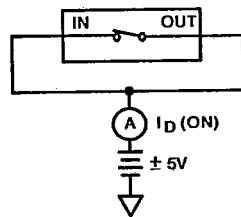
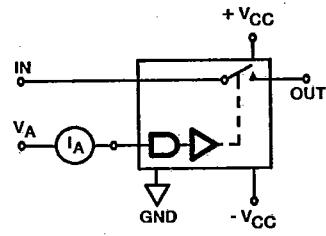
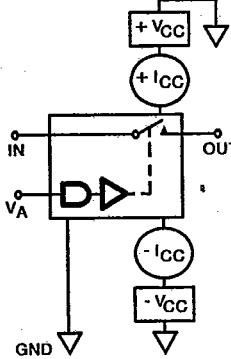
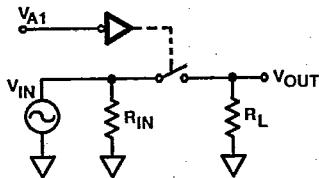
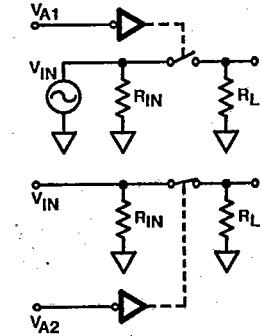
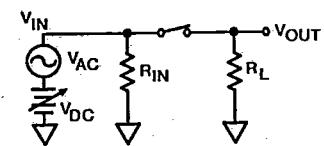
PARAMETERS	SYMBOL	CONDITIONS	NOTES	TEMPERATURE	LIMITS		UNITS
					MIN	MAX	
"On" Resistance Match (Channel to Channel)	$R_{ON}$ Match	$V_D = \pm 5V$ , $I_D = 7.5mA$	1	+25°C	-	5	$\Omega$
Address Capacitance	$C_A$	$V_A = 2.0V, 0.8V$	1	+25°C	-	10	pF
Switch Input Capacitance	$C_{S(OFF)}$	Switch Off: $V_A = 2.0V$	1	+25°C	-	25	pF
Switch Output Capacitance	$C_{D(OFF)}$	Switch Off: $V_A = 2.0V$	1	+25°C	-	60	pF
	$C_{D(ON)}$	Switch On: $V_A = 0.8V$	1	+25°C	-	150	pF
Drain to Source Capacitance	$C_{DS(OFF)}$	Switch Off: $V_A = 2.0V$	1	+25°C	-	2.0	pF
Off Isolation	$V_{ISO}$	$V_S = 300mV_{p-p}$ @ $f = 10MHz$ $R_L = 50\Omega$	1	+25°C	-	-60	dB
CrossTalk	$V_{CT}$	$V_S = 300mV_{p-p}$ @ $f = 10MHz$ $R_L = 50\Omega$	1	+25°C	-	-75	dB
Gain Tolerance	$A_{V\pm}$	$V_S = 300mV_{p-p}$ $R_L = 50\Omega$ @ 1MHz	1	+25°C	-	-0.1	dB
		$V_S = 300mV_{p-p}$ $R_L = 50\Omega$ @ 8MHz	1	+25°C	-	-0.5	dB
Differential Gain	$A_{DIFF}$	$V_S = 300mV_{p-p}$ , $R_L = 2k\Omega$ $V_{OFFSET} = 0V$ to $1V$	1	+25°C	-	0.1	%
Differential Phase	$\Delta_{DIFF}$	$f = 3.58MHz$ and $4.43MHz$	1	+25°C	-	0.01	Degrees

NOTE 1. Parameters listed in Table 3 are controlled via design or process parameters and are not directly tested at final production. These parameters are lab characterized upon initial design release, or upon design changes. These parameters are guaranteed by characterization based upon data from multiple production runs which reflect lot to lot and within lot variation.

TABLE 4. ELECTRICAL TEST REQUIREMENTS

MIL-STD-883 TEST REQUIREMENTS	SUBGROUPS (SEE TABLES 1 & 2)
Interim Electrical Parameters (Pre Burn-in)	1
Final Electrical Test Parameters	1*, 2, 3, 9, 10, 11
Group A Test Requirements	1, 2, 3, 9, 10, 11
Groups C & D Endpoints	1

\* PDA applies to Subgroup 1 only.

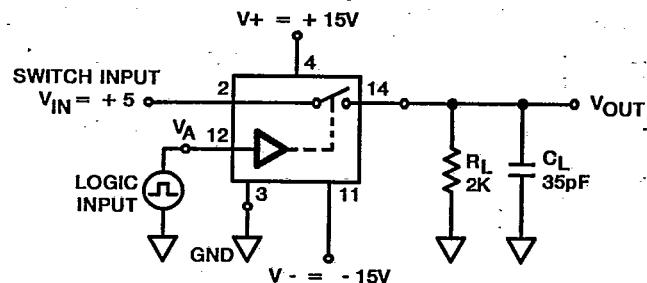
**Test Circuits** $V_{IN} = \pm 5V, I = 7.5mA, V_A = 0.8V$  $V_{IN} = \pm 5V, V_{OUT} = \mp 5V, V_A = 2.0V$  $V_{IN} = \pm 5V, V_{OUT} = \mp 5V, V_A = 2.0V$ **ID(ON)****ADDRESS CURRENT****SUPPLY CURRENTS** $V_{IN} = \pm 5V, V_{OUT} = \pm 5V, V_A = 0.8V$  $V_{AH} = 2.0V, V_{AL} = 0.8V$  $V_A = 0.8V, 2.0V$ **OFF ISOLATION****CROSSTALK****DIFFERENTIAL GAIN, PHASE** $V_{IN} = 300mV_{p-p}, f = 10MHz, R_{IN} = R_L = 50\Omega, V_{A1} = 2.0V$  $V_{IN} = 300mV_{p-p}, f = 10MHz, R_{IN} = R_L = 50\Omega, V_{A1} = 2.0V, V_{A2} = 0.8V$  $V_{AC} = 300mV_{p-p}, f = 3.58MHz \text{ and } 4.43MHz, V_{DC} = 0.0V \text{ to } 1.0V, R_L = 2k\Omega, R_{IN} = 50\Omega$ 

4

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***Test Circuit***

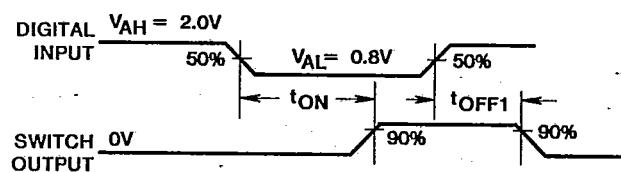
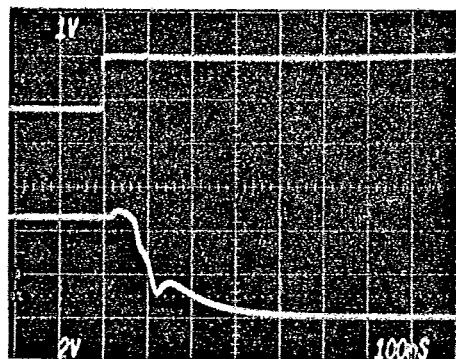
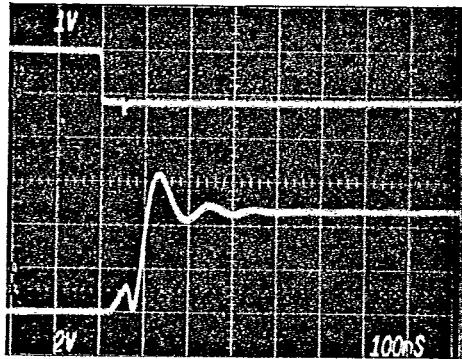
T-51-11

**SWITCHING TEST CIRCUIT ( $t_{ON}$ ,  $t_{OFF1}$ )**

$$V_O \approx V_{IN} \frac{R_L}{R_L + R_{ON}}$$

CL Includes C<sub>FIXTURE</sub> + C<sub>PROBE</sub>**Switching Waveforms**

LOGIC "0" = SWITCH ON

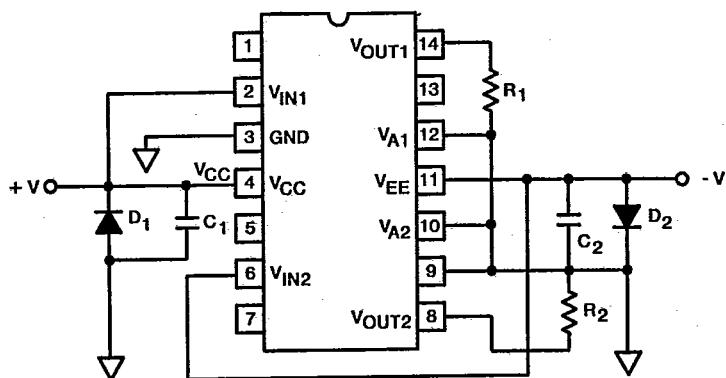
 $t_{ON}$ ,  $t_{OFF1}$  (TTL INPUT),  $V_{AL} = 0.8V$ ,  $V_{AH} = 2.0V$ 

Top: TTL Input (1V/Div.)  
Bottom: Output (2V/Div.)  
Horizontal: 100ns/Div.

## Burn-In Circuits

T-51-11

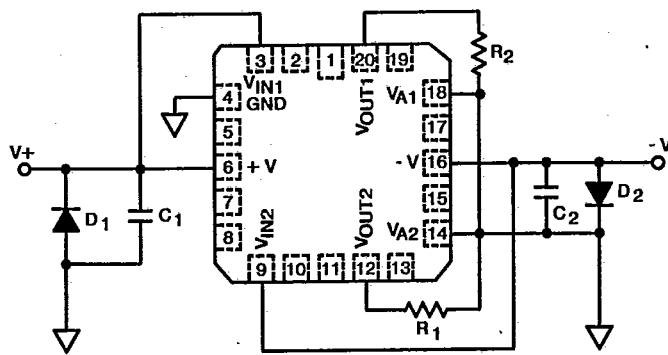
HI-222/883 CERAMIC DIP



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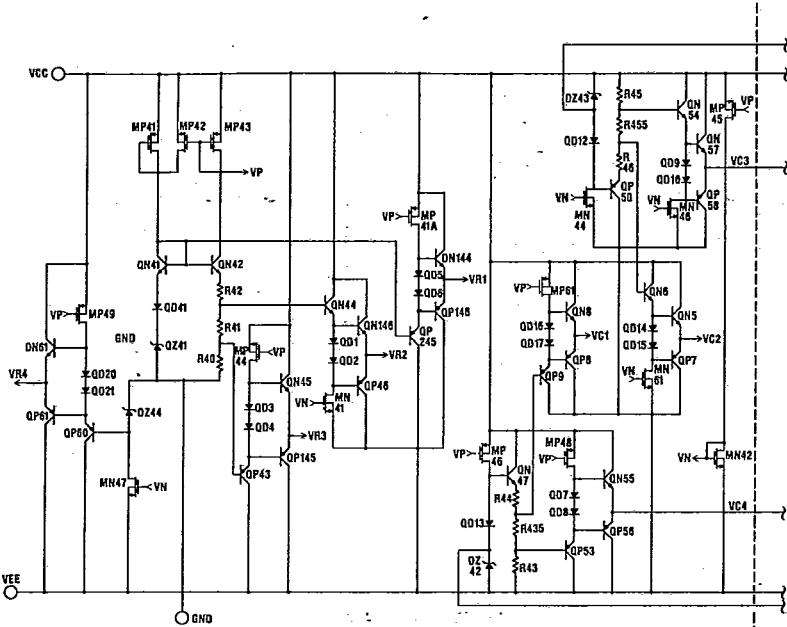
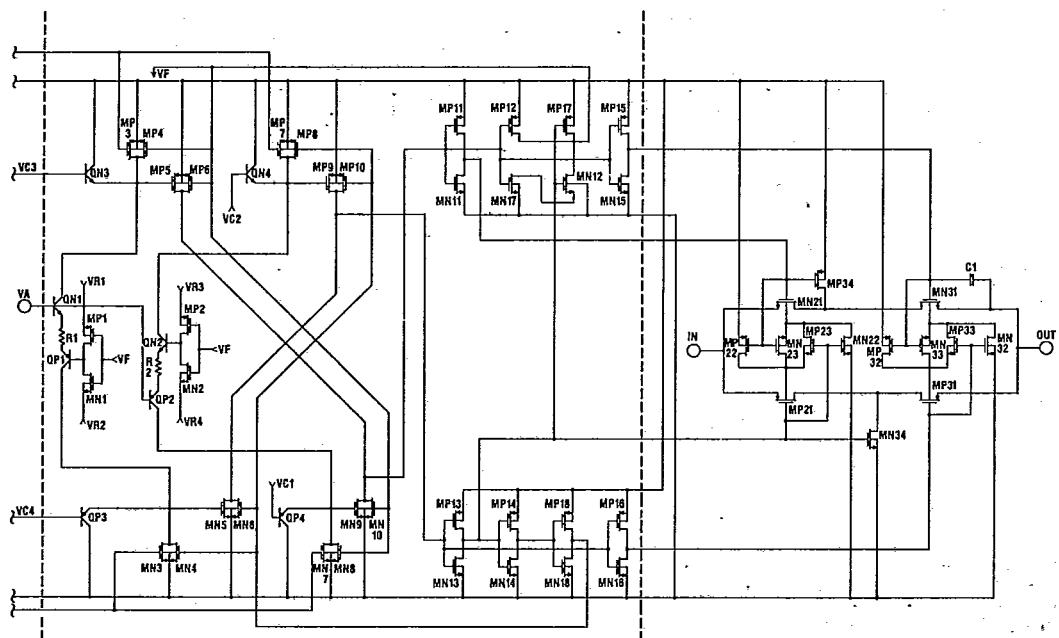
CMOS ANALOG  
SWITCHES

HI-222/883 CERAMIC LCC



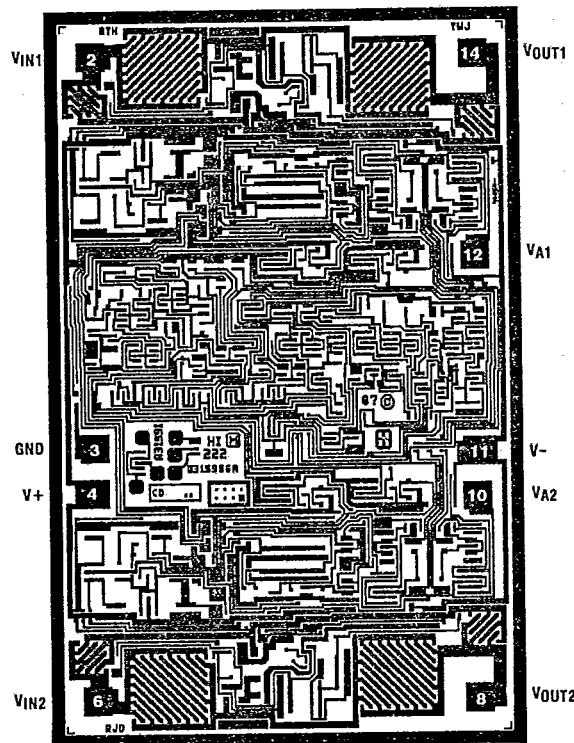
## NOTES:

Both Switches Are On, One Sourcing 1.5mA and the Other Sinking 1.5mA.  
 $R_1 = R_2 = 10k\Omega, \pm 5\%$ , per Socket, 1/4W (Min)  
 $C_1, C_2 = 0.01\mu F/\text{Socket (Min)} \text{ or } 0.1\mu F/\text{Row, (Min)}$   
 $D_1, D_2 = \text{IN4002 or Equivalent/Board}$   
 $|V(+)-(V-) = 30V$   
Pin 9 May Be Tied to Ground or Left Open on Ceramic DIP Circuit.

**Schematic Diagram****BIAS NETWORK****LEVEL SHIFTER****SWITCH**

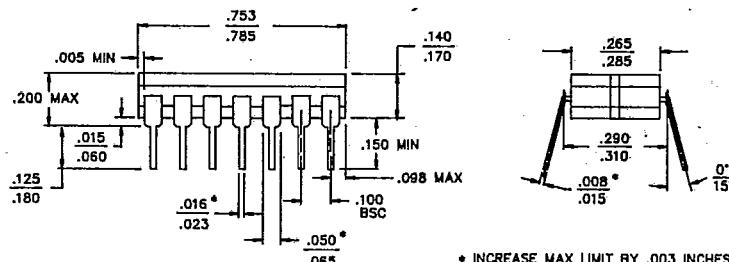
**Die Characteristics****DIE DIMENSIONS:**124 x 79 x 19 mils  
(3120 x 1440 x 480  $\mu\text{m}$ )**METALLIZATION:**Type: Aluminum  
Thickness:  $16\text{k}\text{\AA} \pm 2\text{k}\text{\AA}$ **WORST CASE CURRENT DENSITY:**  
 $0.93 \times 10^5 \text{A/cm}^2$  at 15mA (Continuous)**GLASSIVATION:**Type: Nitride  
Thickness:  $7.0\text{k}\text{\AA} \pm 0.75\text{k}\text{\AA}$ **DEVICE COUNT:** 183**PROCESS:** Silicon Gate/DI**DIE ATTACH:**Material: Gold/Silicon Eutectic Alloy  
Temperature: Ceramic DIP —  $460^\circ\text{C}$  (Max)  
Ceramic LCC —  $420^\circ\text{C}$  (Max)**Metallization Mask Layout**

HI-222/883



NOTE: Pin Numbers Correspond to Ceramic DIP Package Only.

T-51-11

**Packaging<sup>†</sup>****14 PIN CERAMIC DIP**

• INCREASE MAX LIMIT BY .003 INCHES  
MEASURED AT CENTER OF FLAT FOR  
SOLDER FINISH

**LEAD MATERIAL:** Type B**LEAD FINISH:** Type A**PACKAGE MATERIAL:** Ceramic, 90% Alumina**PACKAGE SEAL:**

Material: Glass Frit

Temperature: 450°C ± 10°C

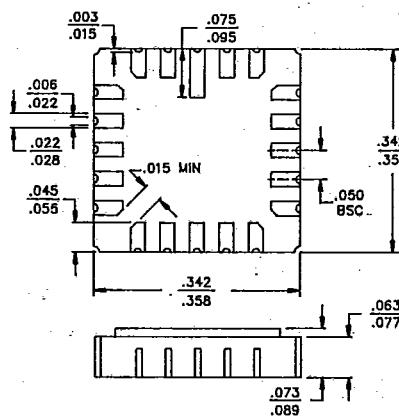
Method: Furnace Seal

**INTERNAL LEAD WIRE:**

Material: Aluminum

Diameter: 1.25 MIL

Bonding Method: Ultrasonic

**COMPLIANT OUTLINE:** 38510 D-1**20 PAD CERAMIC LCC****PAD MATERIAL:** Type C**PAD FINISH:** Type A**FINISH DIMENSION:** Type A**PACKAGE MATERIAL:** Multilayer Ceramic, 90% Alumina**PACKAGE SEAL:**

Material: Gold/Tin (80/20)

Temperature: 320°C ± 10°C

Method: Furnace Braze

**INTERNAL LEAD WIRE:**

Material: Aluminum

Diameter: 1.25 MIL

Bonding Method: Ultrasonic

**COMPLIANT OUTLINE:** 38510 C-2

NOTE: All Dimensions are Min  
Max, Dimensions are in inches.

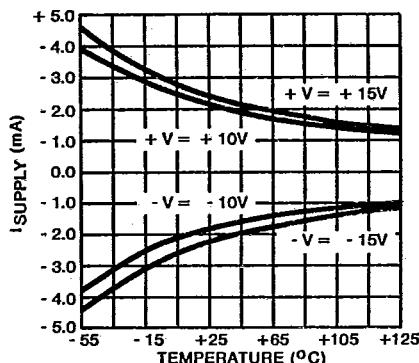
<sup>†</sup>MIL-M-38510 Compliant Materials, Finishes, and Dimensions.

## High Frequency/Video Switch

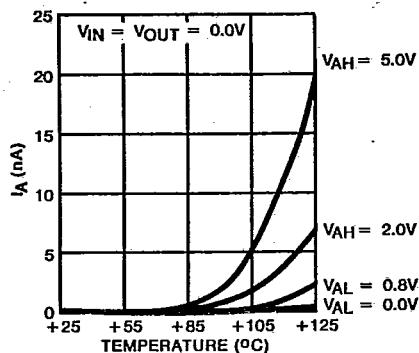
The information contained in this section has been developed through characterization by Harris Semiconductor and is for use as application and design aid only. These characteristics are not 100% tested and no product guarantee is implied.

**Typical Performance Curves** Unless Otherwise Specified:  $T_A = +25^\circ\text{C}$ ,  $V_{SUPPLY} = \pm 15\text{V}$

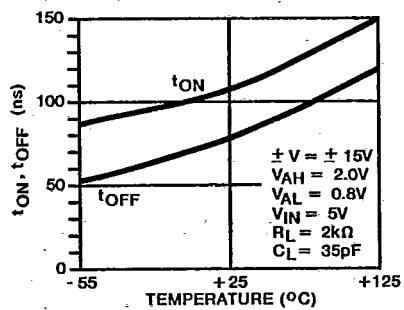
SUPPLY CURRENT vs. TEMPERATURE vs. SUPPLY VOLTAGE



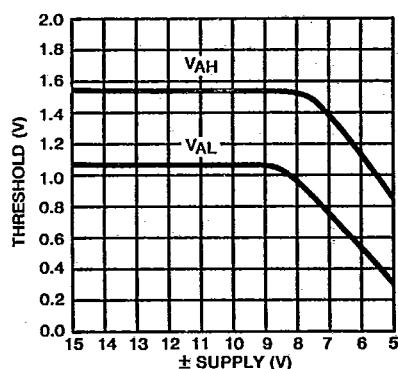
STEADY STATE ADDRESS INPUT CURRENT vs. TEMPERATURE



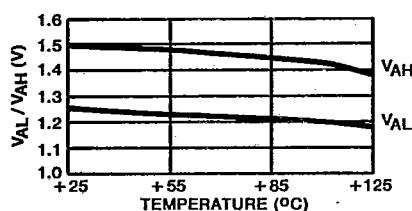
SWITCHING TIME vs. TEMPERATURE



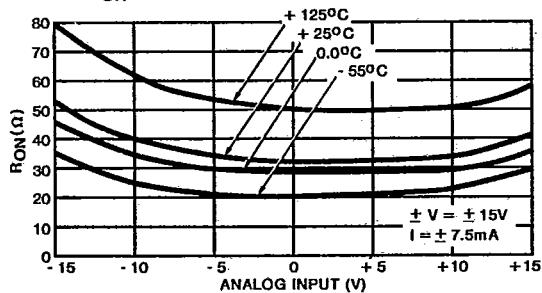
SWITCHING THRESHOLD vs.  $\pm$  SUPPLY VOLTAGE



ADDRESS INPUT THRESHOLD vs. TEMPERATURE



$R_{ON}$  vs. ANALOG INPUT vs. TEMPERATURE

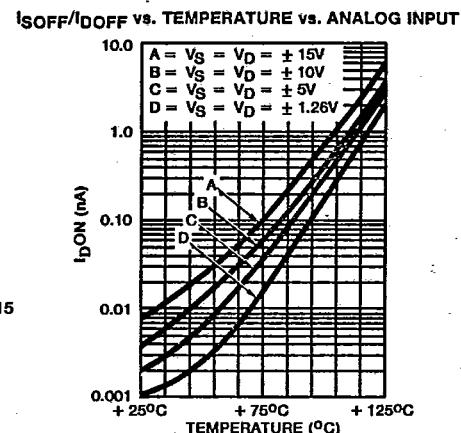
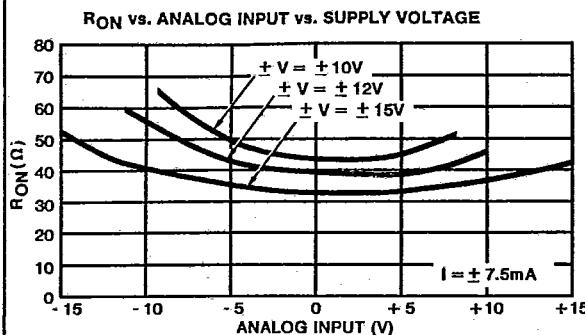


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**CMOS ANALOG SWITCHES**

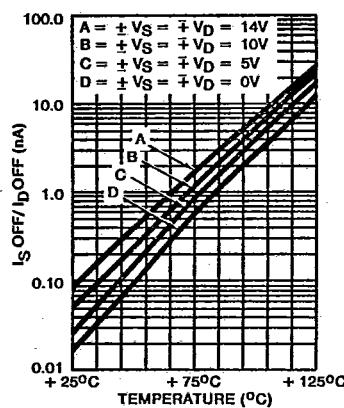
**DESIGN INFORMATION (Continued)**

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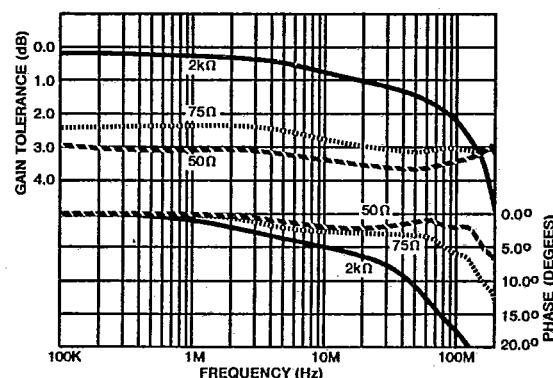
**Typical Performance Curves** Unless Otherwise Specified:  $T_A = +25^\circ\text{C}$ ,  $V_{\text{SUPPLY}} = \pm 15\text{V}$



**$I_{\text{D}\text{ON}}$  vs. TEMPERATURE vs. ANALOG INPUT**



**BANDWIDTH**

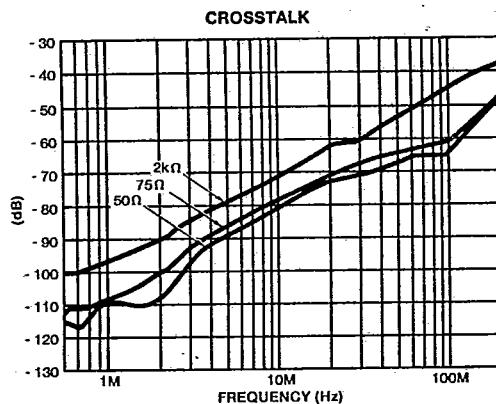
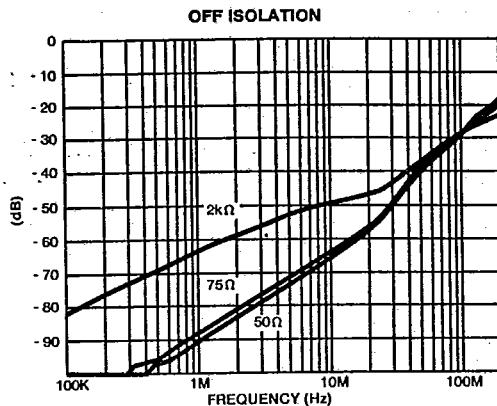
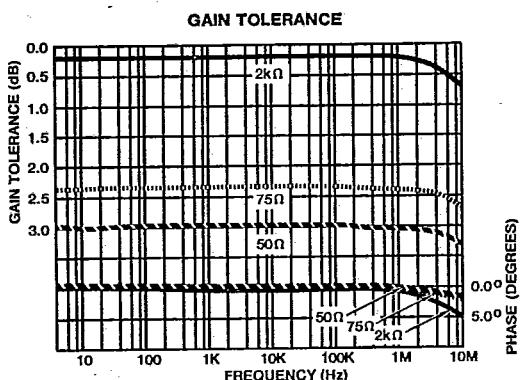


**DESIGN INFORMATION (Continued)**

The information contained in this section has been developed through characterization by Harris Semiconductor and is for use as application and design aid only. These characteristics are not 100% tested and no product guarantee is implied.

**Typical Performance Curves**

Unless Otherwise Specified:  $T_A = +25^\circ\text{C}$ ,  $V_{\text{SUPPLY}} = \pm 15\text{V}$

**TYPICAL PERFORMANCE CHARACTERISTICS**

Device Characterized at: Supply Voltage =  $\pm 15\text{V}$ ,  $R_L = 50\Omega$ , Unless Otherwise Specified.

PARAMETERS	CONDITIONS	TEMP	TYPICAL	UNITS
Differential Gain	$V_S = 300\text{mV}_{\text{p-p}}$ , $V_{\text{Offset}} = 0.0\text{V}$ to $1.0\text{V}$ $f = 3.58\text{MHz}$ , $4.43\text{MHz}$ @ $R_L = 2\text{k}\Omega$	$+25^\circ\text{C}$	0.03	%
	$V_S = 300\text{mV}_{\text{p-p}}$ , $V_{\text{Offset}} = 0.0\text{V}$ to $1.0\text{V}$ $f = 3.58\text{MHz}$ , $4.43\text{MHz}$ @ $R_L = 50\Omega$	$+25^\circ\text{C}$	0.3	%
Differential Phase	$V_S = 300\text{mV}_{\text{p-p}}$ , $V_{\text{Offset}} = 0.0\text{V}$ to $1.0\text{V}$ $f = 3.58\text{MHz}$ , $4.43\text{MHz}$ @ $R_L = 2\text{k}\Omega$	$+25^\circ\text{C}$	0.003	Degrees
	$V_S = 300\text{mV}_{\text{p-p}}$ , $V_{\text{Offset}} = 0.0\text{V}$ to $1.0\text{V}$ $f = 3.58\text{MHz}$ , $4.43\text{MHz}$ @ $R_L = 50\Omega$	$+25^\circ\text{C}$	0.2	Degrees

4  
CMOS ANALOG  
SWITCHES